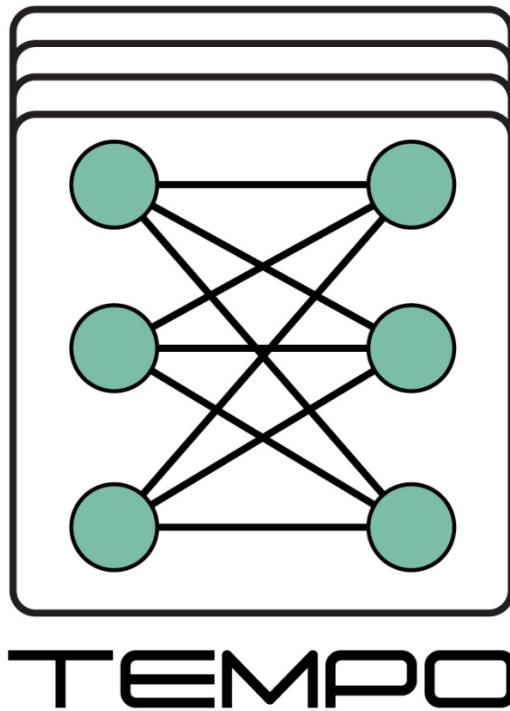Technology & Hardware for nEuromorphic coMPuting
- ECSEL Research and Innovation Actions (RIA*) –

Deliverable 3.7
– Compact Model Generation for PCM (Analog Behavior) –

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ECSEL
Joint Undertaking

1. Public summary

This report describes the model card extraction for PCM based on measurement of Theta material devices detailed in deliverable D3.5. The PCM compact model used is described in [1] and the parameters extraction flow in [2].

The model cards reproduce the experimental median behaviour of the crystalline conduction, the amorph conduction, the melting dynamics and the crystallization dynamics at four temperatures (298K, 313K, 323K and 333K)